

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: McARTHUR, et al.

Serial No.: 10/039,426

Conf. No.: 8965

Filed: January 4, 2002

For: METHOD AND APPARATUS FOR  
PROPER ORDERING OF  
REGISTRATION DATA

Art Unit: 2851

Examiner: Unassigned

I hereby certify that this paper and the attached papers are being deposited with the United States Postal Service as first class mail in an envelope addressed to:

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PRELIMINARY AMENDMENT

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Dear Sir:

Preliminary to examination of the above-captioned patent application, please amend the specification as follows:

IN THE SPECIFICATION:

Please amend the specification as follows (a marked up copy of the amended specification is attached to this Amendment):

Please replace the paragraph at page 3, lines 3-19, with the following:

Figure 5(a) shows a typical overlay displacement vector 502 representing the x-shift and y-shift vector overlay error associated with a misaligned frame-in-frame alignment attribute. In some cases the overlay error can be measured using special in-situ exposure tool metrology See Direct-referencing automatic two-points reticle-to-wafer alignment using a projection column servo system, *supra*. Many